


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/053,202	BAN ET AL.	
	Examiner	Art Unit	
	Yuwen Pan	2682	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
455		556.1		455	556.2	67.11	452.1	452.2	
INTERNATIONAL CLASSIFICATION									
H	0	4	B						
H	0	4	Q						
H	0	4	M						

<i>Yuwen Pan</i> 2/13/06 (Assistant Examiner) (Date)	QUOCHIE B. VUONG PRIMARY EXAMINER <i>Quochien B. Vuong</i> 3/6/06 (Primary Examiner) (Date)	Total Claims Allowed: 19 O.G. Print Claim(s): 1 O.G. Print Fig.: 3823C
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<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
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